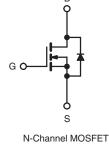


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	400				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	0.20			
Q _g (Max.) (nC)	110				
Q _{gs} (nC)	28				
Q _{gd} (nC)	45				
Configuration	Single				





FEATURES

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30 V V_{GS} Rating
- Reduced C_{iss}, C_{oss}, C_{rss}
- Isolated Central Mounting Hole
- Dynamic dV/dt Rated
- Repetitive Avalanche Rated
- · Lead (Pb)-free Available

DESCRIPTION

This new series of low charge Power MOSFETs achieve significantly lower gate charge over convertional MOSFETs. Utilizing advanced MOSFETs technology the device improvements allow for reduced gate drive requirements, faster switching speeds and increased total system savings. These device improvements combined with the proven ruggedness and reliability of MOSFETs offer the designer a new standard in power transistors for switching applications. The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFP360LCPbF
	SiHFP360LC-E3
SnPb	IRFP360LC
	SiHFP360LC

ABSOLUTE MAXIMUM RATINGS $T_C = 25 \degree C$, unless otherwise noted							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	400	v			
Gate-Source Voltage			V _{GS}	± 30	v		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 \degree C$ $T_C = 100 \degree C$	la la	23				
		T _C = 100 °C	ID	14	А		
Pulsed Drain Currenta			I _{DM}	91			
Linear Derating Factor			2.2	W/°C			
Single Pulse Avalanche Energy ^b			E _{AS}	1200	mJ		
Repetitive Avalanche Current ^a			I _{AR} 23		А		
Repetitive Avalanche Energy ^a			E _{AR} 28		mJ		
Maximum Power Dissipation	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$		PD	280	W		
Peak Diode Recovery dV/dt ^c				4.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)	for	for 10 s 300 ^d		300 ^d	U		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in		
				1.1	N · m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 4.0 mH, R_G = 25 Ω , I_{AS} = 23 A (see fig. 12).

c. $I_{SD} \leq 23$ A, $dI/dt \leq 170$ A/µs, $V_{DD} \leq V_{DS}, \, T_J \leq 150 \ ^{\circ}C.$

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



Vishay Siliconix



PARAMETER	SYMBOL	TYP.		MAX.			UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-				°C/W			
Case-to-Sink, Flat, Greased Surface		0.24		40					
· · ·	R _{thCS}	-							
Maximum Junction-to-Case (Drain)	R _{thJC}	-	- 0.45			<u> </u>			
SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless other	wise noted							
PARAMETER	SYMBOL		CONDITIC	DNS	MIN.	TYP.	MAX.	UNIT	
Static									
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0) V, I _D = 25	i0 μA	400	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	to 25 °C, I	_D = 1 mA	-	0.49	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	/ _{GS} , I _D = 25	50 µA	2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}	Vo	_{as} = ± 20 V	,	-	-	± 100	nA	
		V _{DS} = 400 V, V _{GS} = 0 V		-	-	25			
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 320 V,	V _{DS} = 320 V, V _{GS} = 0 V, T _J = 125 °C		-	-	250	μA	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D	= 14 A ^b	-	-	0.20	Ω	
Forward Transconductance	g _{fs}	V _{DS} = 5	50 V, I _D = 1	4 A ^b	13	-	-	S	
Dynamic							•	1	
Input Capacitance	C _{iss}	,	(_ 0.)(-	3400	-		
Output Capacitance	C _{oss}	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	540	-	pF		
Reverse Transfer Capacitance	C _{rss}			-	42	-			
Total Gate Charge	Qg			A, V _{DS} = 320 V,	-	-	110	nC	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V			-	-	28		
Gate-Drain Charge	Q _{gd}	-	see fig. 6 and 13 ^b		-	-	45	•	
Turn-On Delay Time	t _{d(on)}				-	16	-		
Rise Time	t _r		$V_{DD} = 200 \text{ V}, \text{ I}_D = 23 \text{ A},$ $R_G = 4.3 \ \Omega, \ R_D = 7.9 \ \Omega, \ \text{see fig. } 10^b$		-	75	-	ns	
Turn-Off Delay Time	t _{d(off)}				-	42	-		
Fall Time	t _f				-	50	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH		
Internal Source Inductance	Ls			-	13	-			
Drain-Source Body Diode Characteristic	s							•	
Continuous Source-Drain Diode Current	۱ _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	23	A		
Pulsed Diode Forward Currenta	I _{SM}			-	-	92			
Body Diode Voltage	V _{SD}	$T_J = 25 \ ^{\circ}C, \ I_S = 23 \ A, \ V_{GS} = 0 \ V^b$			-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 23 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	400	600	ns		
Body Diode Reverse Recovery Charge	Q _{rr}			-	5.7	8.6	μC		
Forward Turn-On Time	t _{on}	Intrinsic turr	-on is dor	ninated b	vleand	<u>ما</u>			

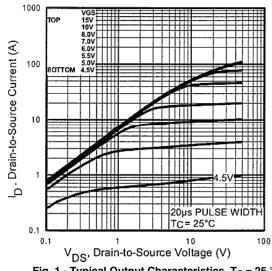
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.

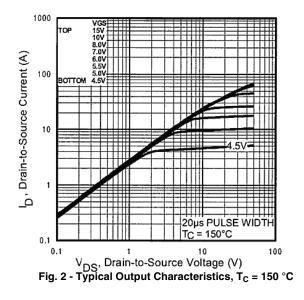


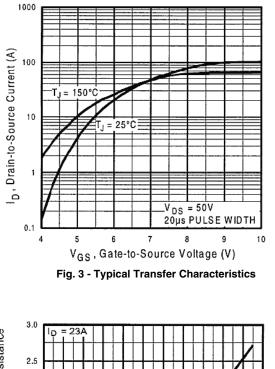
Vishay Siliconix



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted







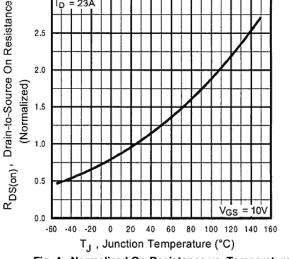


Fig. 4 - Normalized On-Resistance vs. Temperature

Vishay Siliconix



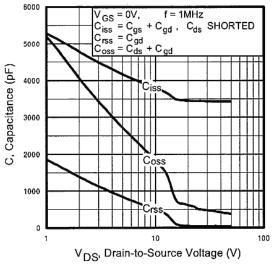
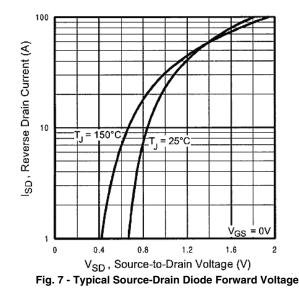
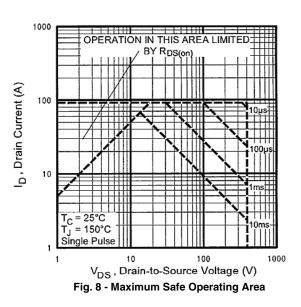
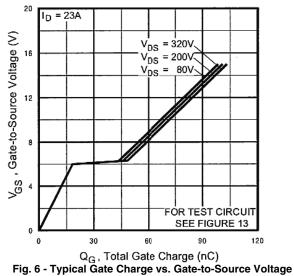


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage









Vishay Siliconix

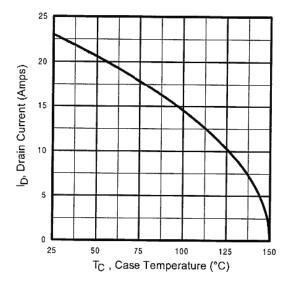


Fig. 9 - Maximum Drain Current vs. Case Temperature

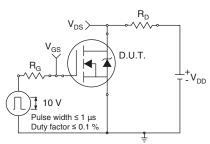


Fig. 10a - Switching Time Test Circuit

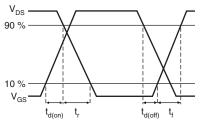


Fig. 10b - Switching Time Waveforms

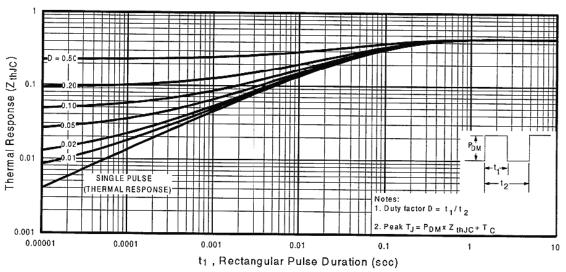


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Vishay Siliconix



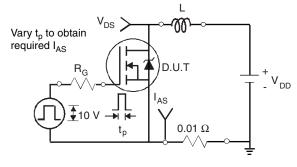


Fig. 12a - Unclamped Inductive Test Circuit

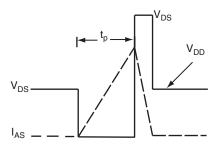


Fig. 12b - Unclamped Inductive Waveforms

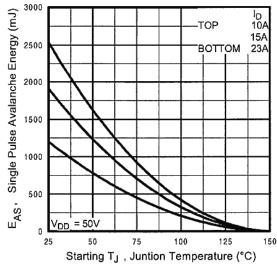
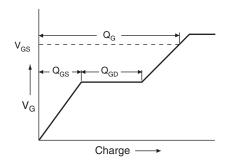


Fig. 12c - Maximum Avalanche Energy vs. Drain Current





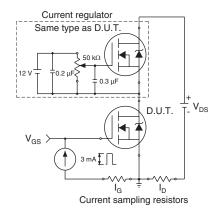
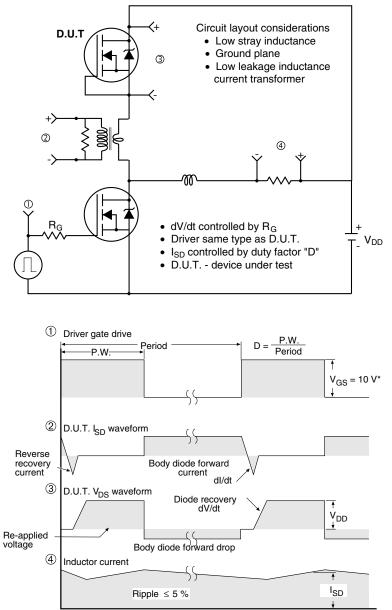


Fig. 13b - Gate Charge Test Circuit



Vishay Siliconix



Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91227.



Vishay

Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.